

FIG. 1 is a schematic diagram of a system for measuring the refractive index of a material. The system includes a light source 10, a beam splitter 20, a sample 30, and a detector 40. The light source 10 emits a beam of light 70 which is split by the beam splitter 20 into two paths. One path 71 passes through the sample 30 and the other path 72 is a reference path. The beams are then recombined and detected by the detector 40. The system is used to measure the refractive index of the sample 30 by comparing the phase of the two beams.

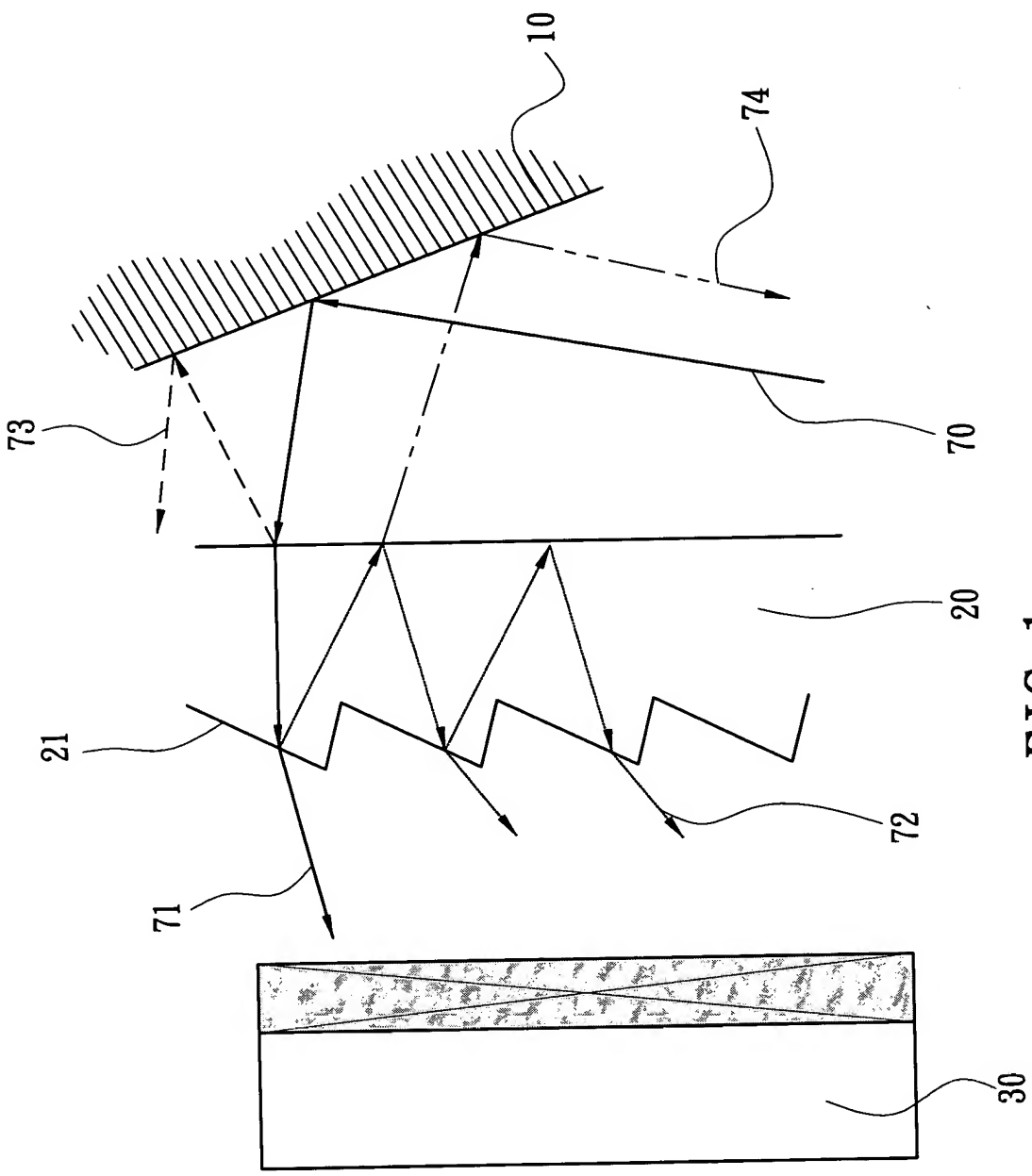


FIG. 1

FIG. 2 is a schematic diagram of a device 100 in a first state. The device 100 includes a first member 21 and a second member 23. The first member 21 is a long, thin, flexible member. The second member 23 is a shorter, thicker, flexible member. The first member 21 is connected to the second member 23 at a joint 27. The joint 27 is a hinge joint. The first member 21 is shown in a curved state, and the second member 23 is shown in a straight state. A third member 50 is shown as a curved line, possibly representing a spring or a cable, connected to the first member 21 and the second member 23. The device 100 is shown in a first state, and the first member 21 is shown in a curved state.

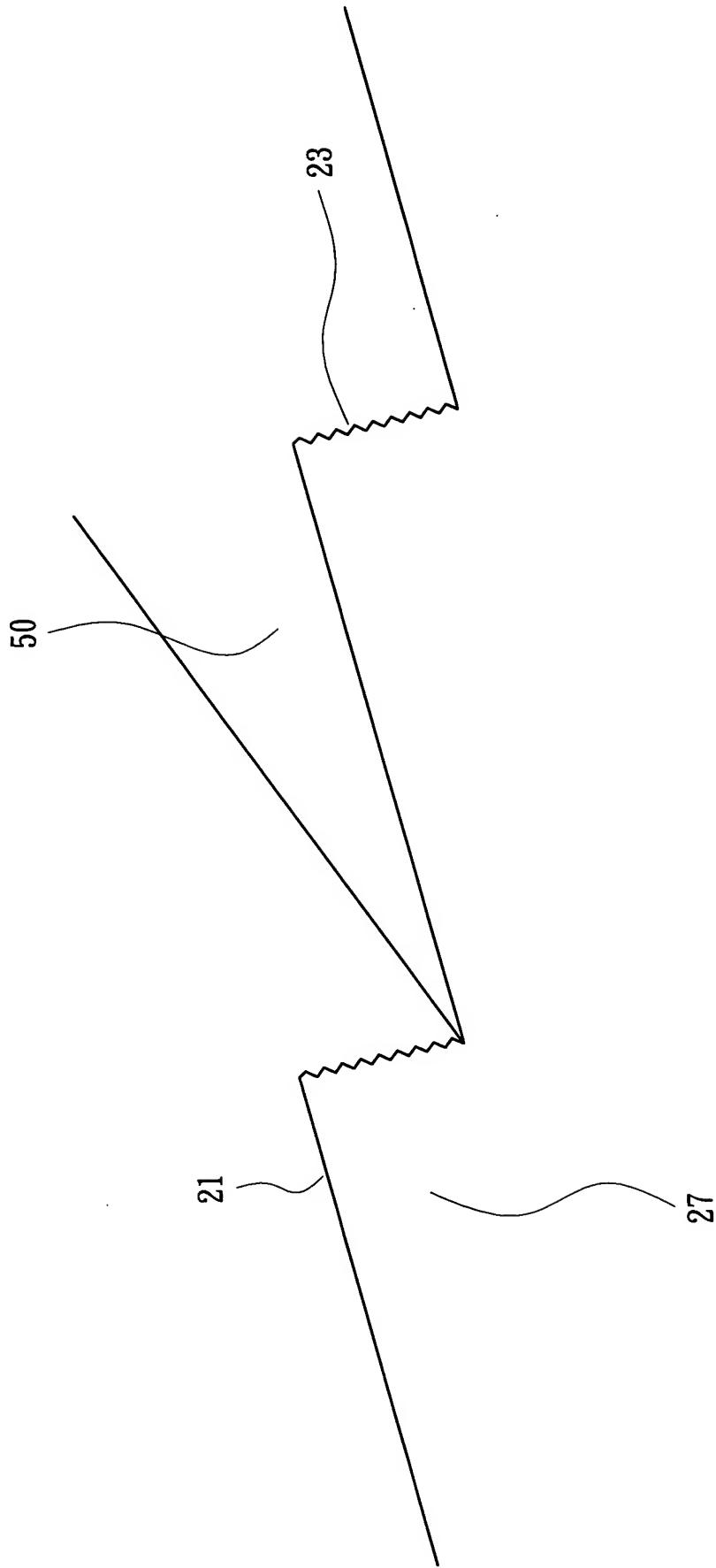


FIG. 2

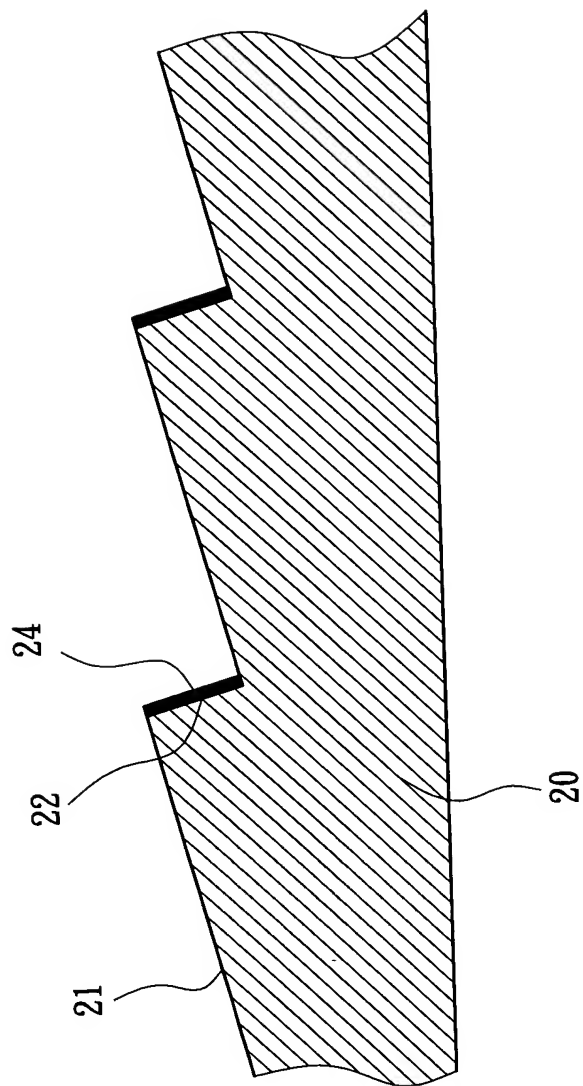


FIG. 3

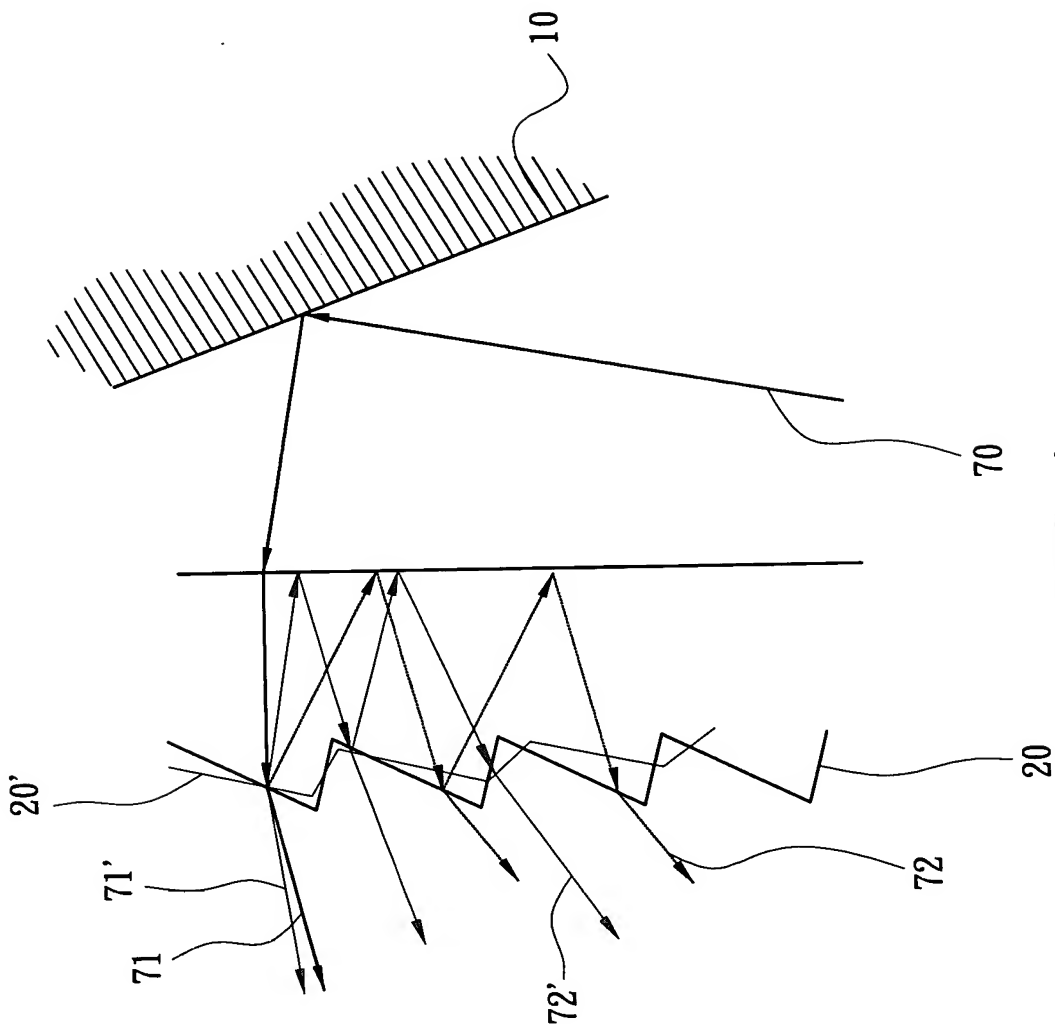


FIG. 4

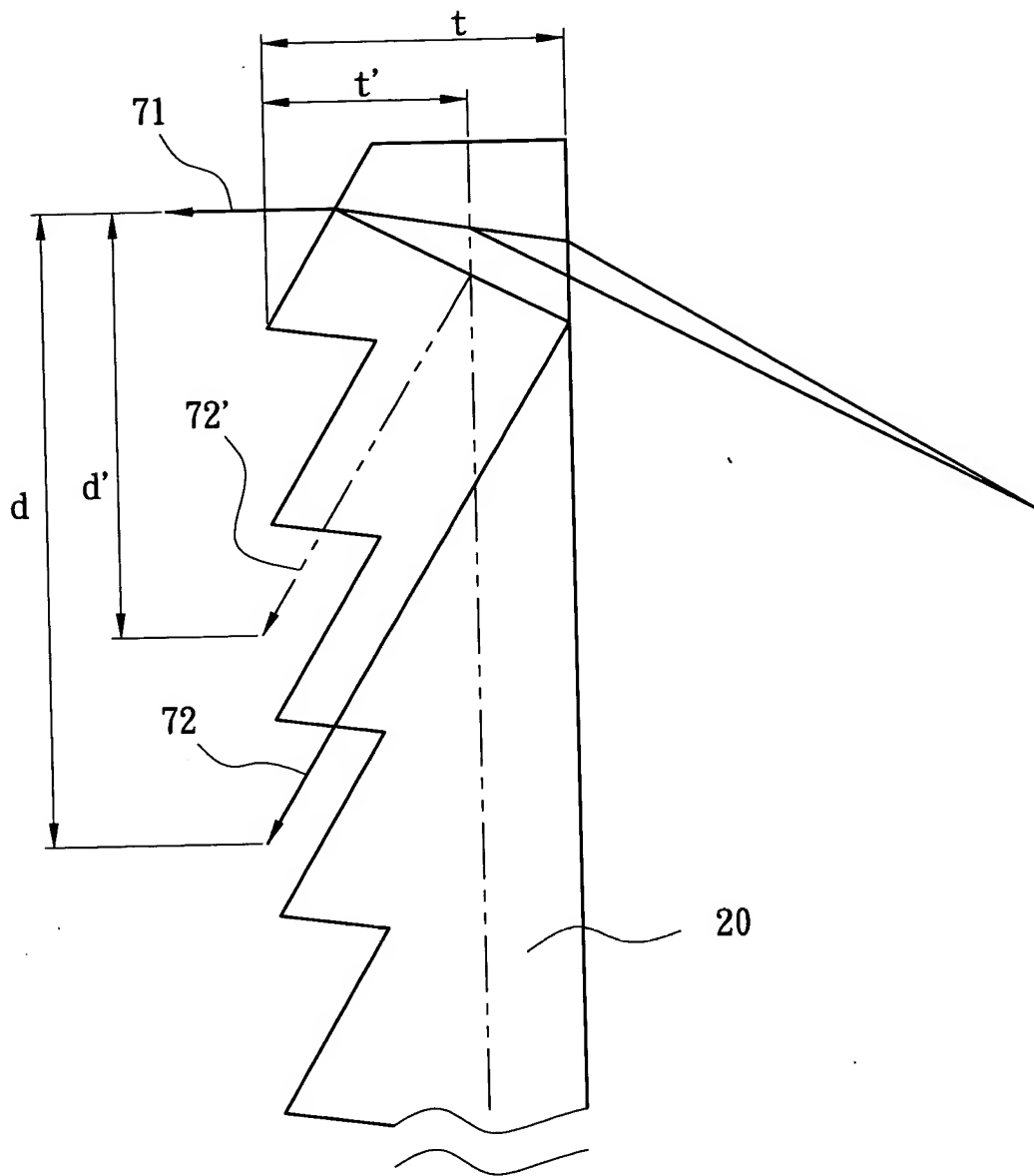


FIG. 5

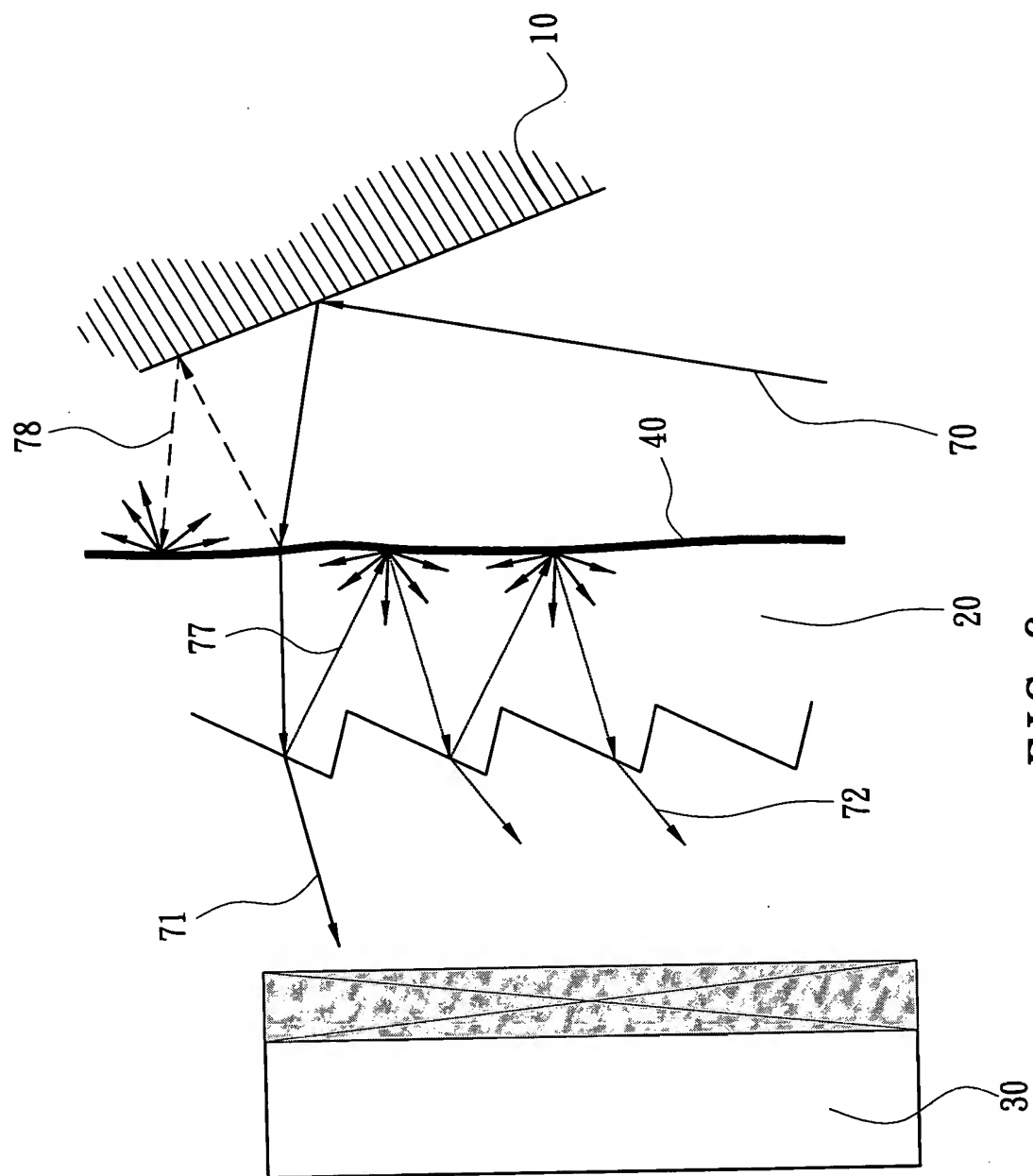


FIG. 6